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| Form PTO 1449 (Rev. 2-32) U.S. Department of Commerce Patent and Trademark Office | Atty. Docket No. 034299-626 | Serial No. 10/528,436 |
|---|---|---|
| **Information Disclosure Statement by Applicant** | Applicant: Gerard Petroz | |
| (Use several sheets if necessary) | Filed: March 18, 2005 | Group: (unassigned) |

**U.S. Patent Documents**

| Init. | | Document No. | Date | Name | Class | Subclass | Filing Date |
|---|---|---|---|---|---|---|---|
| TSP | A | 2,865,793 | 12/23/58 | De Nobel, D. | | | 11/29/55 |
| TSP | B | 6,091,070 | 07/18/00 | Lingren et al. | 250 | 370.09 | 07/03/97 |
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**Foreign Documents**

| Init. | | Document No. | Date | Country | Class | Subclass | Translation Yes | Translation No |
|---|---|---|---|---|---|---|---|---|
| TSP | C | 0 674 348 A1 | 09/27/95 | Europe | | | X | |
| TSP | D | 1 143 213 | 09/27/57 | France (corresponds to U.S. 2,865,793 listed above) | | | | X |

**Other Documents (Including Author, Title, Date, Pertinent Pages, etc.)**

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| TSP | E | Gostilo, V. et al., "Technological aspects of development of pixel and strip detectors based on CdTe and CdZnTe", *NUCLEAR INSTRUMENTS & METHODS IN PHYSICS RESEARCH, SECTION – A: ACCELERATORS, SPECTROMETERS, DETECTORS AND ASSOCIATED EQUIPMENT, NORTH-HOLLAND PUBLISHING COMPANY, Amsterdam, NL,* Vol. 460, No. 1, pages 27-34 (March 11, 2001) |
| TSP | F | Janik, E. et al., "Ohmic contacts to p-type cadmium telluride and cadmium mercury telluride", *JOURNAL OF PHYSICS D: APPLIED PHYSICS,* Vol. 16, pages 2333-2340 (1983) |
| TSP | G | Ponpon, J. P., "A Review of Ohmic and Rectifying Contacts on Cadmium Telluride", *Solid-State Electronics*, Vol. 28, No. 7, pages 689-706 (1985) |
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| Examiner | /Thanhha Pham/ | Date Considered | 06/13/2007 |
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Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include a copy of this form with the next communication to applicant.